

L Number	Hits	Search Text	DB	Time stamp
-	619	700/109,110,148-156.ccls.	USPAT; US-PGPUB	2003/09/30 13:43
-	4	rolling adj2 mill same (steel or metal) same surface same (monitor or inspect)	USPAT; US-PGPUB	2003/09/30 13:47
-	3	surface adj2 defect adj2 map	USPAT; US-PGPUB	2003/09/30 15:42
-	6	surface adj2 defect adj2 distribution	USPAT; US-PGPUB	2003/09/30 15:44
-	6	surface adj2 defect same entropy	USPAT; US-PGPUB	2003/10/01 11:30
-	430	surface adj2 defect same (correlate or classify or group)	USPAT; US-PGPUB	2003/10/01 11:37
-	2	surface adj2 defect same (correlate or classify or group) same filter	USPAT; US-PGPUB	2003/09/30 15:48
-	1	surface adj2 defect same (correlate or classify or group) and entropy	USPAT; US-PGPUB	2003/09/30 15:48
-	3	surface adj2 defect same (correlate or classify or group) same trend	USPAT; US-PGPUB	2003/10/01 13:23
-	29	surface adj2 defect and entropy	USPAT; US-PGPUB	2003/10/01 11:30
-	387	surface adj2 defect same group	USPAT; US-PGPUB	2003/10/01 11:42
-	275	surface adj2 defect same group not (semiconductor or wafer)	USPAT; US-PGPUB	2003/10/01 11:38
-	3	surface adj2 defect same detect same group not (semiconductor or wafer)	USPAT; US-PGPUB	2003/10/01 11:40
-	7	surface adj2 defect same (detect or identify) same group\$3 not (semiconductor or wafer)	USPAT; US-PGPUB	2003/10/01 11:40
-	36	surface adj2 defect same trend	USPAT; US-PGPUB	2003/10/01 13:27
-	2	surface adj2 defect same spc	USPAT; US-PGPUB	2003/10/01 13:28
-	18	surface adj2 defect and spc	USPAT; US-PGPUB	2003/10/01 13:28
-	0	10/030238	USPAT; US-PGPUB	2003/10/01 14:30